

Course Title	ATOMIC FORCE MICROSCOPY
Instructor	Gianpiero Buscarino
N of hours	10
Description	Fundamentals and applications of the Atomic Force Microscopy
Contents	<ul style="list-style-type: none"><li>- Overview of atomic force microscopy (AFM).</li><li>- Tip-surface interaction forces.</li><li>- Introduction to the main AFM scanning modes.</li><li>- Instrumental setups.</li><li>- Laboratory session: determination of the size distribution of nanoparticles distributed on a flat surface.</li></ul>